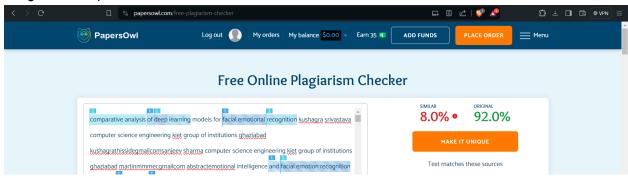
Plagiarism Report:



IEEE Xplore ScreenShot:

